



5/9/2009

**RELIABILITY MONITOR REPORT
FOR**

Dallas 0.35 μ m "D" Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS1080CL	DS1081L
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 14335** **FITS: 8.0**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2008 and 12/31/2008.

Process Information:

Process Description: Dallas 0.35µm "D" Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0734	DS1081L	125C, 3.6 VOLTS	1000 HRS	77	0	VK715647ADO
HIGH TEMP OP LIFE	0811	DS1080CL	125C, 3.6 VOLTS	1000 HRS	45	0	QD823625BB-NPI
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0734	DS1081L	150C	1000 HRS	77	0	VK715647ADO
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BOND STRENGTH	0734	DS1081L	MIL-STD-883-2011 : COND D	40 WIRES	5	0	VK715647ADO
TEMP CYCLE, 5' RAMP, 10' DWELL	0734	DS1081L	-65C TO 150C	500 CYS	77	0	VK715647ADO
Total:						0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HAST	0734	DS1081L	130C, 85%R.H.,3.5V	96 HRS	77	0	VK715647ADO
Total:						0	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
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